

*Citations for :* **Dielectric Targets** *Ion = O*

<b>Pub. Year</b>	<b>Authors, Title, Journal Citation and Comments</b>	<b>Citation Numb</b>
<b>1960</b>	Schambra, P. E. Rauth, A. M. Northcliffe, L. C. <b>'Energy Loss Measurements for Heavy Ions in Mylar and Polyethylene'</b> <i>Phys. Rev., 120, 1758 (1960)</i> <i>Comment : S, He, B, Be, C, N, O, F, Ne (10 MeV/amu) -&gt; Mylar, Polyethylene</i>	<b>1960-Scha2</b>
<b>1970</b>	Santry, D. C. Sitter, C. W. <b>'Range and Retention Studies of 40-keV Ions in Solids, in H'</b> <i>Wagner, W. Walcher (Ed.) Proc. Int. Conf. Elmagn. Isotope Separators and Their Techniques. Marburg, P. 505-24 (1970)</i> <i>Comment : R, dR. 40 keV C, O, P, Co, Tl, Na, P, Co, Zn, Se, Kr, Hf, Cs, Ag, I, Xe -&gt; Au, W, WO3</i>	<b>1970-Sant</b>
<b>1974</b>	EerNisse, E. P. <b>'Compaction of Ion Implanted Fused Silica'</b> <i>J. Appl. Phys., 45, 167-174 (1974)</i> <i>Comment : R, H, He, O, Ne, Ar (150-300 keV) -&gt; SiO2 One of the earliest SiO2 compaction studies.</i>	<b>1974-EerN</b>
<b>1975</b>	Tsai, J. C. C. Morabito, J. M. <b>'In-Depth Profile Detection Limits of Nitrogen in GaP and Nitrogen, Oxygen, and Fluorine in Si by SIMS and AES'</b> <i>Ion Implantation in Semiconductors, Namba (ed.), Plenum, N. Y. P. 115-24 (1975)</i> <i>Comment : R, dR. 50 keV N -&gt; GaP, Si; 50 keV O, F -&gt; Si</i>	<b>1975-Tsai</b>
<b>1976</b>	L'Hoir, A. Cohen, C. Amsel, G. <b>'Experimental Study of the Stopping Power and Energy Straggling of MeV 4He, 12C, 14N and 16O Ions in Amorphous Aluminum Oxide'</b> <i>Meyer, G. Linker and F. Kappeler (Ed.): Ion Beam Surface Layer Analysis, Plenum, N. Y., P. 965-76 (1976)</i> <i>Comment : S, dS. 0.3-1.7 MeV He, 12C, 14N, 16O -&gt; Al2O3</i>	<b>1976-L</b>
<b>1978</b>	Stephens, K. G. Wilson, I. H. <b>'Properties and Applications of Ion-Implanted Films'</b> <i>Thin Solid Films, 50, 325-347 (1978)</i> <i>Comment : R. 30 keV O -&gt; Ta205, 60-80 keV Ar -&gt; Ta</i>	<b>1978-Step</b>
<b>1987</b>	Gauvin, H. Bimbot, R. Herault, J. Anne, R. Bastin, G. <b>'Stopping Powers of Solids for 16O Ions at Intermediate Energies (20-95 MeV/amu)'</b> <i>Nucl. Inst. Methods, B28, 191-194 (1987)</i> <i>Comment : S. O (20-95 MeV/amu) -&gt; Be, Al, Si, Ti, Ni, Cu, Ag, Ta, Au, Mylar</i>	<b>1987-Gauv</b>
<b>1987</b>	Raisanen, J. Rauhala, E. <b>'Stopping of Havar, Nickel, Kapton and Mylar for 5-19 MeV 16O Ions'</b> <i>Phys. Rev. B, 36 (18) 9776-9780 (1987)</i> <i>Comment : S. O(5-19 MeV) -&gt; Ni, Kapton, Havar, Mylar</i>	<b>1987-Rais</b>

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<b>1988</b>	Balanzat, E. Jousset, J. C. Toulemonde, M. <b>'Latent Tracks Induced by Heavy Ions in the GeV Energy Range: Results at GANIL'</b> <i>Nucl. Inst. Methods, B32, 368-376 (1988)</i> Comment : R. O, Ar, Kr, Mo, Xe, U (4-85 MeV/amu) -> Polymers, Insulators, Superconductors: Track Analysis	<b>1988-Bala</b>
<b>1990</b>	Kumar, S. Sharma, S. K. Garg, A. K. Sharma, A. P. <b>'Experimental Range of Heavy Ions of Charge 6-28 in CR-39 and Lexan'</b> <i>Appl. Rad. Isotopes (UK), 41, 497-500 (1990)</i> Comment : R. C, N, O, Ne, Si, Fe, Ni (6-9 MeV/amu) -> CR-39, Lexan	<b>1990-Kuma</b>
<b>1990</b>	Raisanen, J. Rauhala, E. <b>'Stopping Powers and Energy Loss of Mylar, Kapton, Havar and Ni for 10 Ions (Z= 3-17) in the Energy Range 0.2-2.1 MeV/amu'</b> <i>Phys. Rev. B, 41, 3951-3958 (1990)</i> Comment : S. B, C, N, O, Al, Si, P, Cl (0.2-2.1 MeV/amu) -> Mylar, Kapton, Havar, Ni	<b>1990-Rais</b>
<b>1990</b>	Rauhala, E. Raisanen, J. <b>'Stopping Powers of Li, B, C, O Ions in C16H14O3 Polycarbonate'</b> <i>Phys. Rev. B, 42, 3877-3880 (1990)</i> Comment : S. Li, B, C, N, O (0.5-2.1 MeV/amu) -> Polycarbonate	<b>1990-Rauh</b>
<b>1992</b>	Rauhala, E. Raisanen, J. Fulop, Zs. Kiss, A. Z. Hunyadi, I. <b>'Slowing Down of Light Ions in LR-115 Nuclear Track Material'</b> <i>Nucl. Tracks Rad. Meas. (UK), 20, 611-614 (1992)</i> Comment : S. H, He, Li, B, C, N, O (0.3-4.3 MeV/amu) -> LR-115 (nuclear track material)	<b>1992-Rauh</b>
<b>1993</b>	Jin, C. Lu, X. Huang, X. Ye, Y. Xia, Z. <b>'Stopping Power of Mylar for Low Velocity B-11, C-12 and O-16 Ions'</b> <i>Phys. Rev. B, 48, 6858-5861 (1993)</i> Comment : S. B, C, O (1.0-6.0 MeV) -> Mylar	<b>1993-Jin 2</b>
<b>1994</b>	Raisanen, J. Rauhala, E. Fulop, Z. Kiss, A. Z. Somorjai, E. <b>'Stopping Powers of CR-39 Nuclear Track Material for Z=1-14 Ions with 0.25-2.8 MeV/amu'</b> <i>Rad. Meas. (UK), 23, 749-752 (1994)</i> Comment : S. Z=1-14 (0.25-2.8 MeV/amu) -> CR-39	<b>1994-Rais2</b>
<b>1994</b>	Wu, A. Lu, X. Jin, C. Zheng, T. <b>'Energy Straggling Measurements of O and F Ions in Au and CaF2'</b> <i>Chinese Phys. Letters, 11, 605-608 (1994)</i> Comment : dS. O, F (1-10 MeV) -> Au, CaF2	<b>1994-Wu</b>
<b>1994</b>	Wu, A. Lu, X. Jin, C. Zheng, T. Xia, Z. <b>'Stopping Power of compounds for O and F Ions'</b> <i>Chinese Phys. Letters, 11, 537-540 (1994)</i> Comment : S. O, F -> Ca and Mo Compounds	<b>1994-Wu 2</b>

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<b>2000</b>	Angulo, C. Delbar, Th. Graulich, J.-S. Leleux, P. <b>'Stopping Powers of Ions at 1 MeV per Nucleon'</b> <i>Nucl. Instl. Methods, V170, 21-27 (2000)</i> <i>Comment : S, Be, B, C, N, O, F, Ne (1 MeV/u) -&gt; C, Al, Ni, CH2, PVC</i>	<b>2000-Angu</b>